MOTOROLA SEMICONDUCTOR TECHNICAL DATA

Designer's Data Sheet

Power Field Effect Transistor

P-Channel Enhancement **Mode Silicon Gate TMOS**

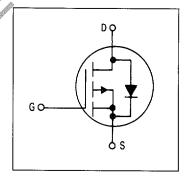
These TMOS Power FETs are designed for medium voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

- Silicon Gate for Fast Switching Speeds Switching Times Specified at 100°C
- Designer's Data IDSS, VDS(on), VGS(th) and SOA Specified at Elevated Temperature
- Rugged SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive

MTH20P08 MTH20P10 MTM20P08 MTM20P10



TMOS POWER FETS 20 AMPERES $r_{DS(on)} = 0.15 OHM$ 80 and 100 VOLTS



MAXIMUM RATINGS

at Elevated Temperature Rugged — SOA is Power Dissipation Lir Source-to-Drain Diode Characterized for Loads	nited			
MAXIMUM RATINGS	MTM a	nd MTH	T	
Rating	Symbol	20P08	20P10	Unit
Drain-Source Voltage	V _{DSS}	80	100	Vdc
Drain-Gate Voltage (RGS = 1 MΩ)	V _{DGR}	80	100	Vdc
Gate-Source Voltage	V _{GS}	± 20		Vdc
Drain Current Continuous Pulsed	I _{DM}	20 80		Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	PD	125 1		Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-65 to 150		°C

THERMAL CHARACTERISTICS

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Thermal Resistance Junction to Case Junction to Ambient	R _θ JC R _θ JA	1 30	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	TL	275	°C



MTM20P08 MTM20P10 **CASE 1-04 TO-204AA** (TO-3)



MTH20P08 MTH20P10 **CASE 340-01** TO-218AC

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.





DS3700

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Charac	teristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (VGS = 0, ID = 0.25 mA)	MTH20P08, MTM20P08 MTH20P10, MTM20P10	V(BR)DSS	80 100	_	Vdc
Zero Gate Voltage Drain Current $(V_{DS} = Rated V_{DSS}, V_{GS} = 0)$ $(V_{DS} = 0.8 Rated V_{DSS}, V_{GS} = 0)$	T _J = 125°C)	IDSS		0.2 1	mAdc
Gate-Body Leakage Current, Forward $(V_{GSF} = 20 \text{ Vdc}, V_{DS} = 0)$		IGSSF	_	100	nAdc
Gate-Body Leakage Current, Reverse $(V_{GSR} = 20 \text{ Vdc}, V_{DS} = 0)$		^I GSSR		100	nAdc
N CHARACTERISTICS*		<u>,</u>			
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_{D} = 1 \text{ mA})$ $T_{J} = 100^{\circ}\text{C}$		V _{GS(th)}	2 1.5	4.5 4	Vdc
Static Drain-Source On-Resistance (VGS = 10 Vdc, ID = 10 Adc)		rDS(on)		0.15	Ohm
Drain-Source On-Voltage ($V_{GS} = 10$ ($I_{D} = 20$ Adc) ($I_{D} = 10$ Adc, $T_{J} = 100^{\circ}$ C)	V)	VDS(on)	<u>-</u>	3.2 3	Vdc
Forward Transconductance $(V_{DS} = 1 \text{ V}, I_{D} = 10 \text{ A})$		9fs	5	_	mhos
YNAMIC CHARACTERISTICS				,,,	
Input Capacitance		C _{iss}	_	2000	pF
Output Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz})$	Coss	_	950	
Reverse Transfer Capacitance		C _{rrs}	_	400	
WITCHING CHARACTERISTICS* $(\top_J$ =	= 100°C)				
Turn-On Delay Time		t _d (on)		45	ns
Rise Time	$(V_{DD} = 25 \text{ V}, I_D = 0.5 \text{ Rated } I_D$	t _r	-	200	
Turn-Off Delay Time	R _{gen} = 50 ohms) See Figures 12 and 13	t _{d(off)}		150	
Fall Time		tf	_	150	
Total Gate Charge	(V _{DS} = 0.8 Rated V _{DSS} , I _D = Rated I _D , V _{GS} = 10 V)	Qg	52 (Typ)	75	nC
Gate-Source Charge		Qgs	22 (Typ)	_	
Gate-Drain Charge	See Figure 11	Q _{gd}	30 (Typ)	_	
OURCE DRAIN DIODE CHARACTERIS	TICS*				,
Forward On-Voltage	(Is = Rated ID	V _{SD}	2.8 (Typ)	4	Vdc
Forward Turn-On Time	VGS = 0) See Figures 15 and 16	ton	100 (Typ)	_	ns
Reverse Recovery Time		t _{rr}	350 (Typ)	_	ns

^{*}Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

TYPICAL ELECTRICAL CHARACTERISTICS

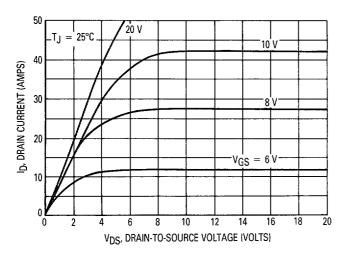


Figure 1. On-Region Characteristics

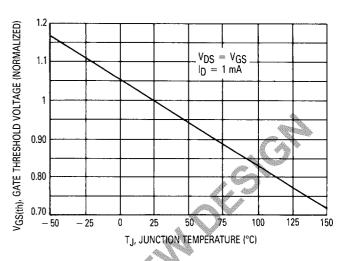


Figure 2. Gate-Threshold Voltage Variation
With Temperature

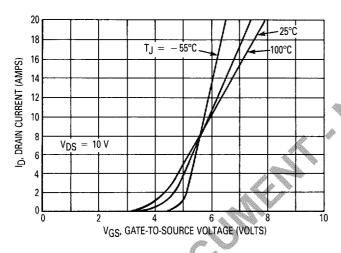


Figure 3. Transfer Characteristics

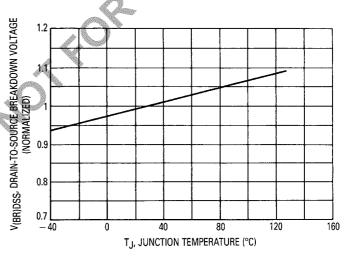


Figure 4. Breakdown Voltage Variation
With Temperature

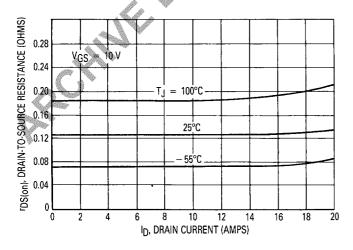


Figure 5. On-Resistance versus Drain Current

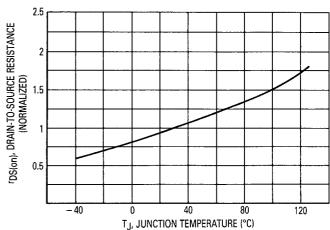


Figure 6. On-Resistance Variation With Temperature

SAFE OPERATING AREA INFORMATION

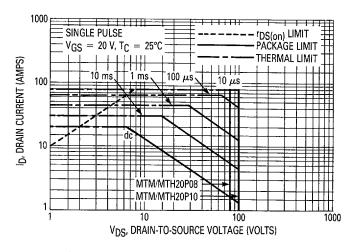


Figure 7. Maximum Rated Forward Biased Safe Operating Area

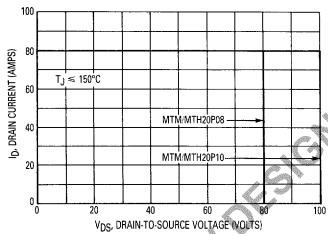


Figure 8. Maximum Rated Switching Safe Operating Area

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain-to-source voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, I_{DM} and the breakdown voltage, $V_{(BR)DSS}$. The switching SOA shown in Figure 8 is applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

The power averaged over a complete switching cycle must be less than:

$$\frac{T_{J(max)} - T_{C}}{R_{\theta JC}}$$

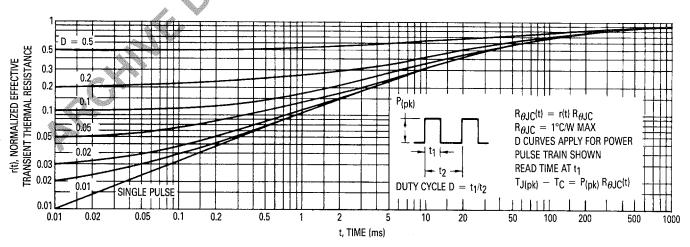
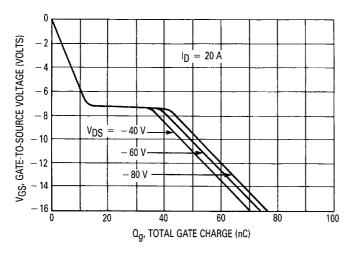


Figure 9. Thermal Response



2500
2000
2000
Ciss
TJ = 25°C
VGS = 0
T = 1 MHz

Coss
VDS, DRAIN-TO SOURCE VOLTAGE (VOLTS)

Figure 10. Capacitance Variation

Figure 11. Gate Charge versus Gate-To-Source Voltage

RESISTIVE SWITCHING

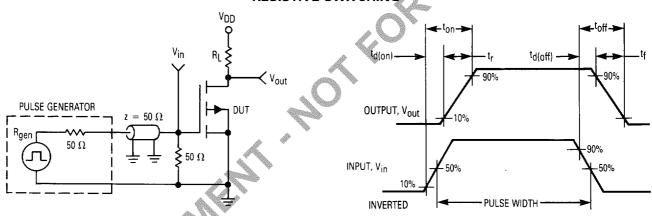
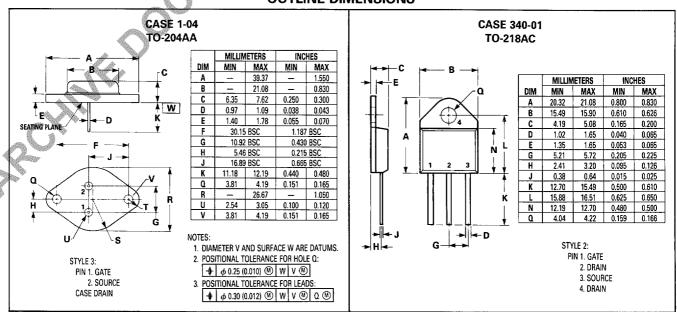


Figure 12. Switching Test Circuit

Figure 13. Switching Waveforms

OUTLINE DIMENSIONS



TMOS SOURCE-TO-DRAIN DIODE CHARACTERISTICS

In the fabrication of a TMOS FET, a diode is formed across the source-to-drain terminals as shown in Figure 14. Reversal of the drain voltage will cause current flow in the reverse direction. This diode may be used in circuits

requiring external fast recovery diodes, therefore, typical characteristics of the on voltage, forward turn-on and reverse recovery times are given.

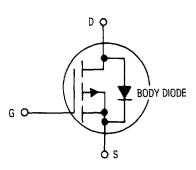


Figure 14. TMOS FET With Source-To-Drain Diode

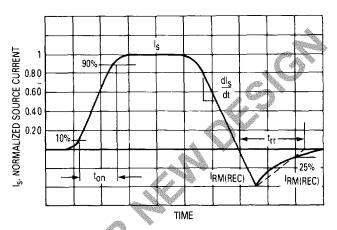


Figure 15. Diode Switching Waveform

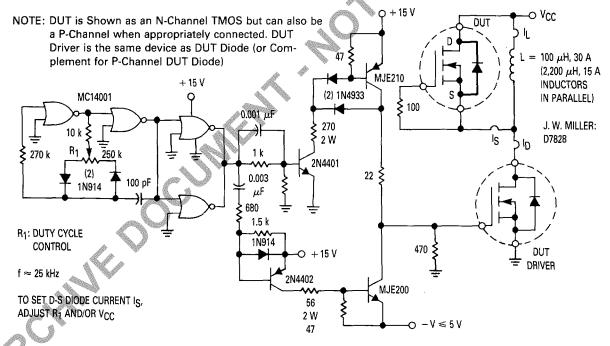


Figure 16. TMOS Diode Switching Test Circuit

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